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Accel-RF's New RF Fixture for Characterization of Compound Semiconductor Devices

SAN DIEGO--([BUSINESS WIRE](#))--Accel-RF, the worldwide leader in turn-key RF Reliability and Performance Characterization Test Systems for Compound Semiconductors, announces the addition of a new 'Smart Fixture' product-line for performance characterization of compound semiconductor devices.

This USB controlled fixture, complete with either custom matching circuits, or proprietary wide bandwidth bias-tees, includes an embedded heater, and integrated analog/digital control board for temperature setting and DC/RF pulsing setup. The fixture has an *innovative* clamping system that will allow for electrical, mechanical, and RF contact of the device-under-test without "hard-mounting" of the package and leads. The configuration is capable of use with several different thermal imaging systems, including micro-raman spectroscopy, for channel-temperature measurement under active bias, temperature, and RF stimulation.

"The smart fixture from Accel-RF allows our customers to manage the stimulus to their RF device on a bench-top setting to control the base-plate or channel-temperature, DC bias, and RF signal to specific test conditions. This opens an avenue to quickly characterize device performance on numerous levels. These performance metrics can be for **intrinsic reliability studies, performance degradation studies, or for parameter variation analysis**" says Roland Shaw, President and co-founder of Accel-RF. "This off-the-shelf solution provides a standard fixture with the capability to adapt to as many as 11 different package types and allowing our customer to get on with the task of testing the device without the issue of developing a new fixture for each application", adds Shaw.

Available immediately, Accel-RF's smart fixture is used by technology developers, RF engineers, and reliability engineers to characterize their devices in a thermally controlled, RF friendly environment. The fixture has the same footprint as the RF fixture in the Accel-RF Reliability Test System. The "Smart Fixture" utilizes Accel-RF's Lifetest™ Software for the graphical user interface and data analysis and presentation capability.

"With the Smart Fixture we offer a *plug-n-play solution* for testing performance characteristics of individual devices and technologies in a fast and accurate manner. **At Accel-RF we pride ourselves in understanding our customers' needs and offering solutions to meet those needs**", concludes Shaw.

About Accel-RF

Accel-RF Corporation is a closely-held private corporation located in San Diego, California. The company specializes in the development, design, and production of accelerated life-test/burn-in test systems for RF semiconductor devices. These systems are turn-key integrated instruments that provide a cost-effective and high-value proposition for manufacturers, fabless designers, testing-service providers, original equipment manufacturers, system integrators, and research and development laboratories requiring intrinsic reliability identification, process-control validation, specification standard-deviation characterization, and product qualification testing.

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